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 Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,875	ENDO ET AL.
Examiner	Art Unit
Alex Liew	2624

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
382/106,154 limited to text search	4/23/2007	AL
348/36-39 limited to text search	4/23/2007	AL
382/274 limited to text search	4/25/2007	AL